

**Search Notes**

Application/Control No.

10/757,901

Examiner

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Applicant(s)/Patent under  
Reexamination

OIKAWA ET AL.

Art Unit

1762

**SEARCHED**

Class	Subclass	Date	Examiner
428	629,632, 668,669	12/4/2006	AB

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
427	127-128	12/4/2006	AB
427	130	12/4/2006	AB
427	132	12/4/2006	AB
428/ 629,632, 668,669		12/4/2006	ab

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
previous search updated	12/4/2006	AB
inspected file wrapper 10/008,743	12/4/2006	ab